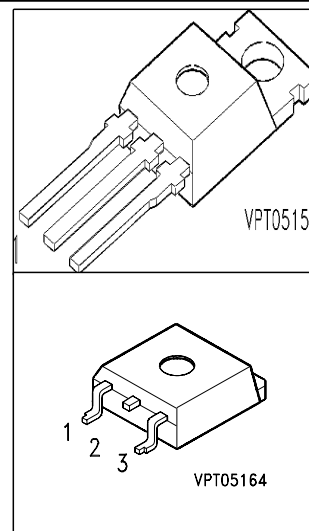
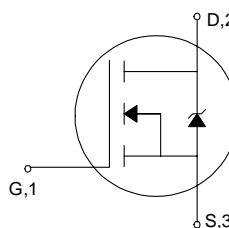


## Cool MOS™ Power-Transistor

- New revolutionary high voltage technology
- Ultra low gate charge
- Periodic avalanche rated
- Extreme  $dv/dt$  rated
- Optimized capacitances
- Improved noise immunity
- Former development designation:  
SPPx3N60S5/SPBx3N60S5



Type	$V_{DS}$	$I_D$	$R_{DS(on)}$	Package	Marking	Ordering Code
SPP07N60S5	600 V	7.3 A	0.6 $\Omega$	P-TO220-3-1	07N60S5	Q67040-S4172
SPB07N60S5				P-TO263-3-2	07N60S5	Q67040-S4185

### Maximum Ratings, at $T_j = 25\text{ }^{\circ}\text{C}$ , unless otherwise specified

Parameter	Symbol	Value	Unit
Continuous drain current $T_C = 25\text{ }^{\circ}\text{C}$ $T_C = 100\text{ }^{\circ}\text{C}$	$I_D$	7.3 4.6	A
Pulsed drain current, $t_p = 1\text{ ms}^{1)}$ $T_C = 25\text{ }^{\circ}\text{C}$	$I_{D\text{ puls}}$	14.6	
Avalanche energy, single pulse $I_D = 7.3\text{ A}$ , $V_{DD} = 50\text{ V}$	$E_{AS}$	230	mJ
Avalanche energy (repetitive, limited by $T_{jmax}$ ) $I_D = 9.1\text{ A}$ , $V_{DD} = 50\text{ V}$	$E_{AR}$	0.8	
Avalanche current (repetitive, limited by $T_{jmax}$ )	$I_{AR}$	9.1	A
Reverse diode $dv/dt$ $I_S = 7.3\text{ A}$ , $V_{DS} < V_{DSS}$ , $di/dt = 100\text{ A}/\mu\text{s}$ , $T_{jmax} = 150\text{ }^{\circ}\text{C}$	$dv/dt$	6	kV/ $\mu\text{s}$
Gate source voltage	$V_{GS}$	$\pm 20$	V
Power dissipation $T_C = 25\text{ }^{\circ}\text{C}$	$P_{tot}$	83	W
Operating and storage temperature	$T_j, T_{stg}$	-55... +150	$^{\circ}\text{C}$

**Electrical Characteristics**, at  $T_j = 25\text{ °C}$ , unless otherwise specified

Parameter	Symbol	Values			Unit
		min.	typ.	max.	

**Thermal Characteristics**

Thermal resistance, junction - case	$R_{thJC}$	-	-	1.5	K/W
Thermal resistance, junction - ambient (Leaded and through-hole packages)	$R_{thJA}$	-	-	62	
SMD version, device on PCB: @ min. footprint @ 6 cm <sup>2</sup> cooling area <sup>2)</sup>	$R_{thJA}$	- -	- 35	62 -	

**Static Characteristics**, at  $T_j = 25\text{ °C}$ , unless otherwise specified

Drain-source breakdown voltage $V_{GS} = 0\text{ V}$ , $I_D = 0.25\text{ mA}$	$V_{(BR)DSS}$	600	-	-	V
Gate threshold voltage, $V_{GS} = V_{DS}$ $I_D = 350\text{ }\mu\text{A}$ , $T_j = 25\text{ °C}$	$V_{GS(th)}$	3.5	4.5	5.5	
Zero gate voltage drain current, $V_{DS} = V_{DSS}$ $V_{GS} = 0\text{ V}$ , $T_j = 25\text{ °C}$ $V_{GS} = 0\text{ V}$ , $T_j = 150\text{ °C}$	$I_{DSS}$	- -	0.5 -	1 100	$\mu\text{A}$
Gate-source leakage current $V_{GS} = 20\text{ V}$ , $V_{DS} = 0\text{ V}$	$I_{GSS}$	-	-	100	nA
Drain-source on-state resistance $V_{GS} = 10\text{ V}$ , $I_D = 4.6\text{ A}$	$R_{DS(on)}$	-	0.54	0.6	$\Omega$

<sup>1</sup>current limited by  $T_{jmax}$ 
<sup>2</sup> Device on 40mm\*40mm\*1.5mm epoxy PCB FR4 with 6 cm<sup>2</sup> (one layer, 70 $\mu\text{m}$  thick) copper area for drain connection. PCB is vertical without blown air.

**Electrical Characteristics**, at  $T_j = 25\text{ }^{\circ}\text{C}$ , unless otherwise specified

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	

### Dynamic Characteristics

Transconductance	$g_{fs}$	$V_{DS} \geq 2 \cdot I_D \cdot R_{DS(on)max}$ , $I_D = 4.6\text{A}$	-	4	-	S
Input capacitance	$C_{iss}$	$V_{GS} = 0\text{V}$ , $V_{DS} = 25\text{V}$ , $f = 1\text{MHz}$	-	970	-	pF
Output capacitance	$C_{oss}$		-	370	-	
Reverse transfer capacitance	$C_{rss}$		-	10	-	
Turn-on delay time	$t_{d(on)}$	$V_{DD} = 350\text{V}$ , $V_{GS} = 10\text{V}$ , $I_D = 7.3\text{A}$ , $R_G = 12\Omega$	-	120	-	ns
Rise time	$t_r$		-	40	-	
Turn-off delay time	$t_{d(off)}$		-	170	255	
Fall time	$t_f$		-	20	30	

### Gate Charge Characteristics

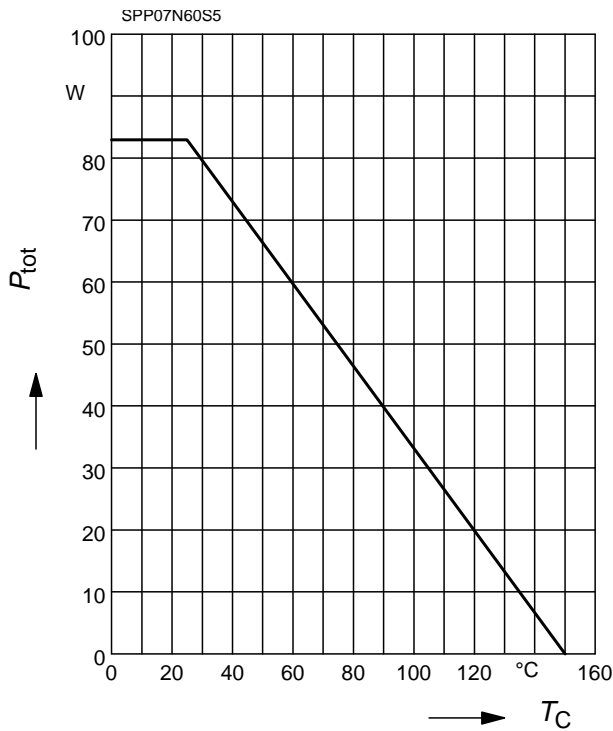
Gate to source charge	$Q_{gs}$	$V_{DD} = 350\text{V}$ , $I_D = 7.3\text{A}$	-	7.5	-	nC
Gate to drain charge	$Q_{gd}$		-	16.5	-	
Total gate charge	$Q_g$	$V_{DD} = 350\text{V}$ , $I_D = 7.3\text{A}$ , $V_{GS} = 0\text{ to }10\text{V}$	-	27	35	

### Reverse Diode

Inverse diode continuous forward current	$I_S$	$T_C = 25^{\circ}\text{C}$	-	-	7.3	A
Inverse diode direct current, pulsed	$I_{SM}$		-	-	14.6	
Inverse diode forward voltage	$V_{SD}$	$V_{GS} = 0\text{V}$ , $I_F = 7.3\text{A}$	-	1	1.2	V
Reverse recovery time	$t_{rr}$	$V_R = 350\text{V}$ , $I_F = I_S$ , $di_F/dt = 100\text{A}/\mu\text{s}$	-	750	1275	ns
Reverse recovery charge	$Q_{rr}$		-	4.9	-	$\mu\text{C}$

### Power dissipation

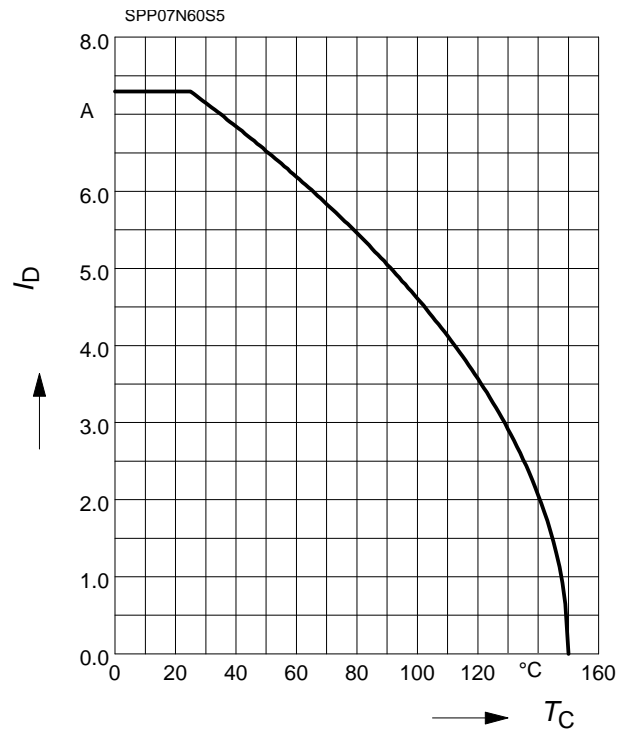
$$P_{\text{tot}} = f(T_C)$$



### Drain current

$$I_D = f(T_C)$$

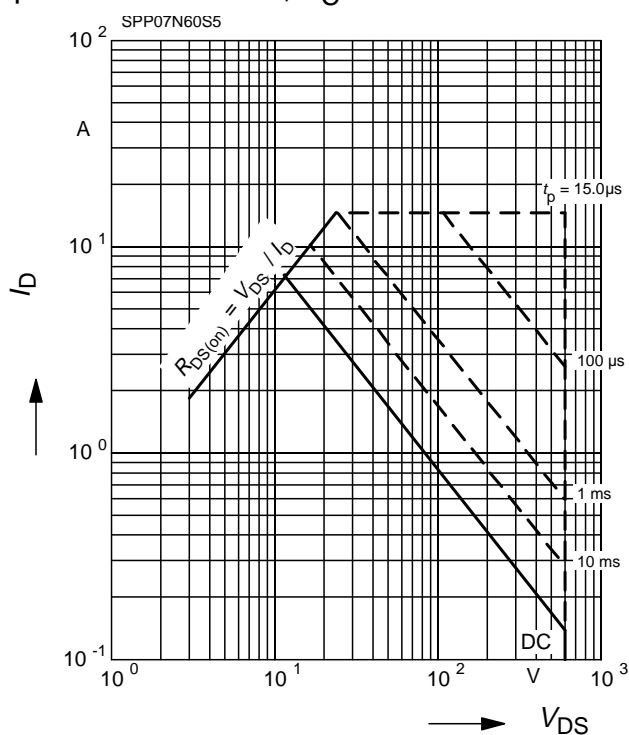
parameter:  $V_{GS} \geq 10 \text{ V}$



### Safe operating area

$$I_D = f(V_{DS})$$

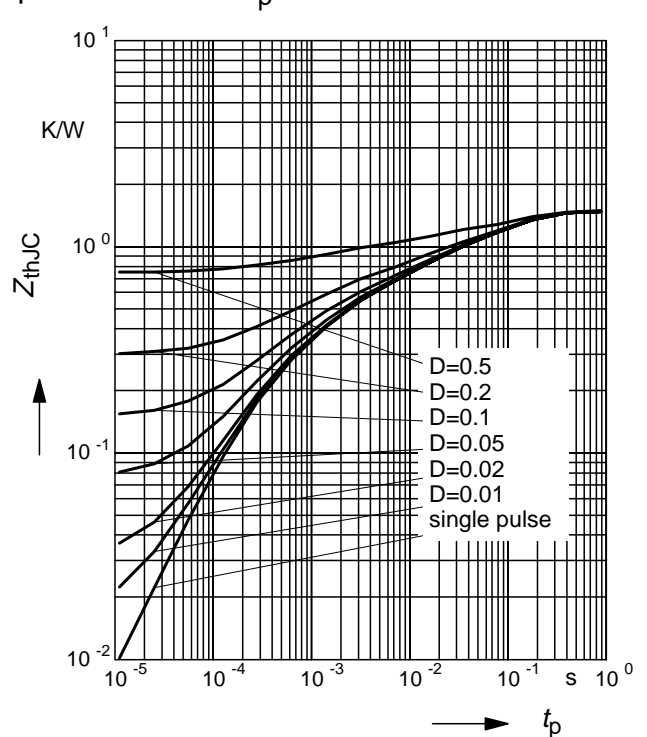
parameter:  $D=0.01$ ,  $T_C=25^\circ\text{C}$



### Transient thermal impedance

$$Z_{\text{thJC}} = f(t_p)$$

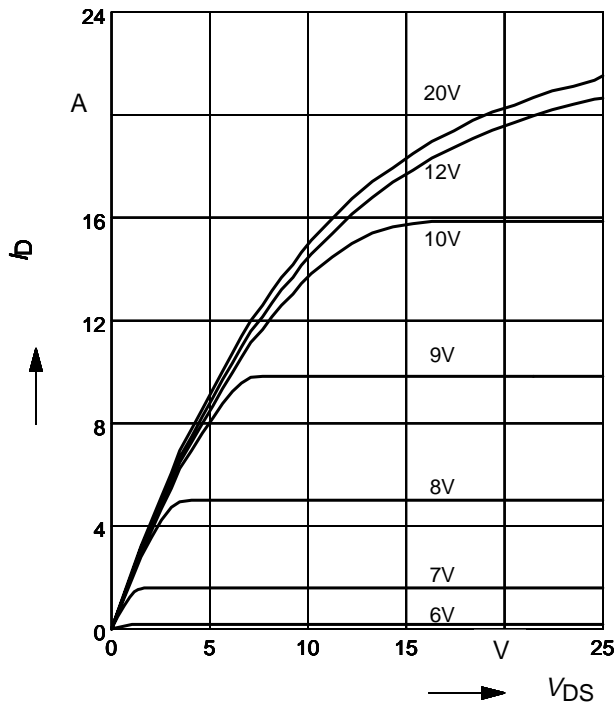
parameter:  $D = t_p / T$



### Typ. output characteristic

$$I_D = f(V_{DS})$$

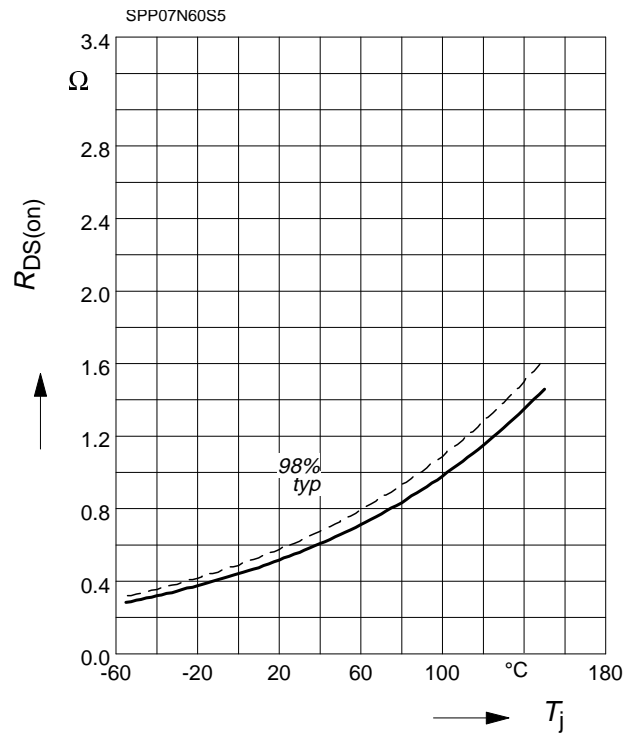
Parameter:  $V_{GS}$ ,  $T_j = 25^\circ\text{C}$



### Drain-source on-resistance

$$R_{DS(on)} = f(T_j)$$

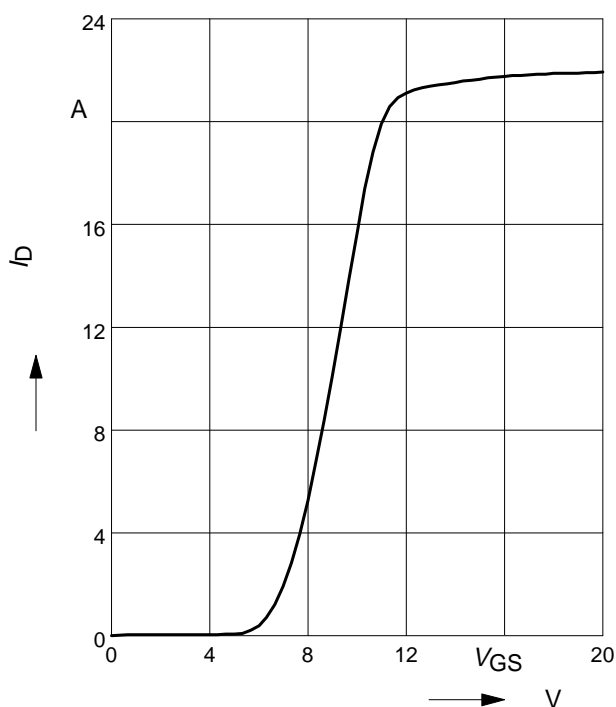
parameter:  $I_D = 4.6\text{ A}$ ,  $V_{GS} = 10\text{ V}$



### Typ. transfer characteristics

$$I_D = f(V_{GS})$$

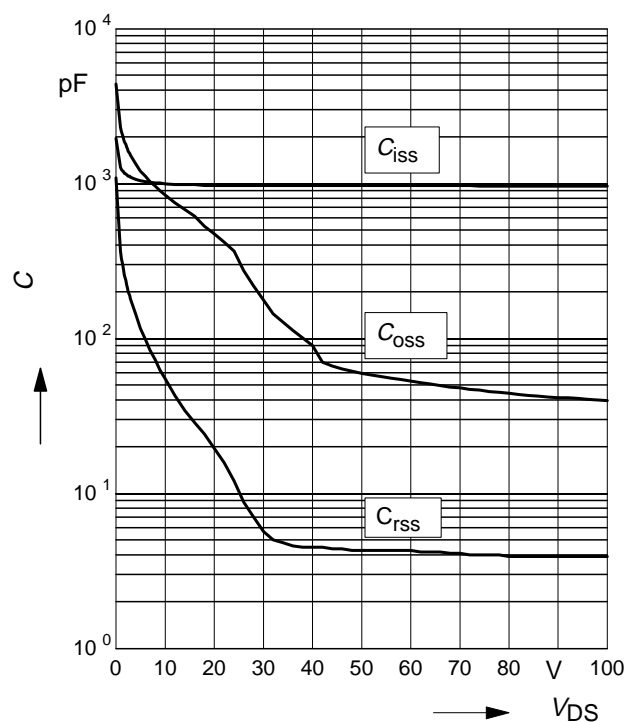
$V_{DS} \geq 2 \times I_D \times R_{DS(on)max}$



### Typ. capacitances

$$C = f(V_{DS})$$

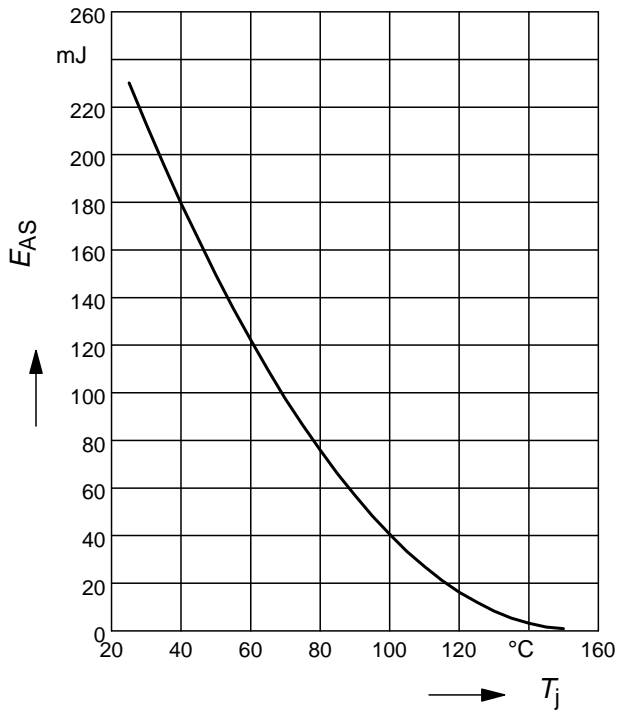
parameter:  $V_{GS} = 0\text{ V}$ ,  $f = 1\text{ MHz}$



### Avalanche energy

$$E_{AS} = f(T_j)$$

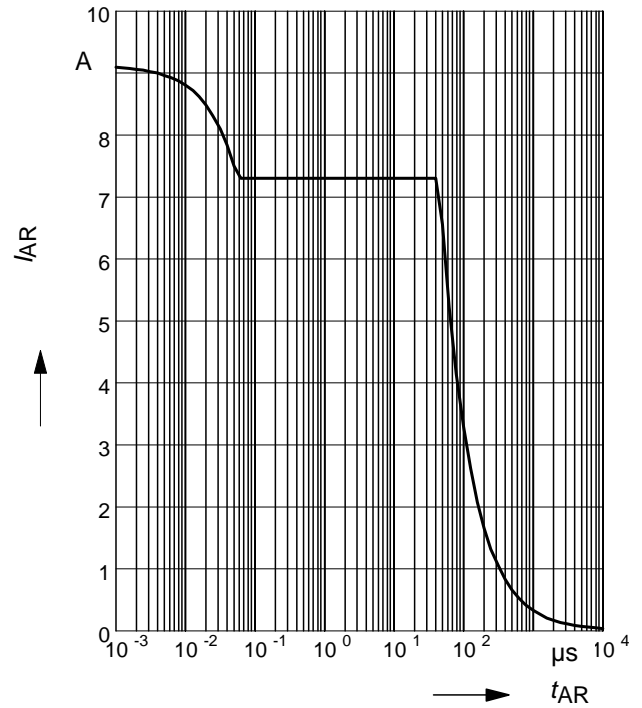
par.:  $I_D = 7.3A$ ,  $V_{DD} = 50V$



### Avalanche SOA

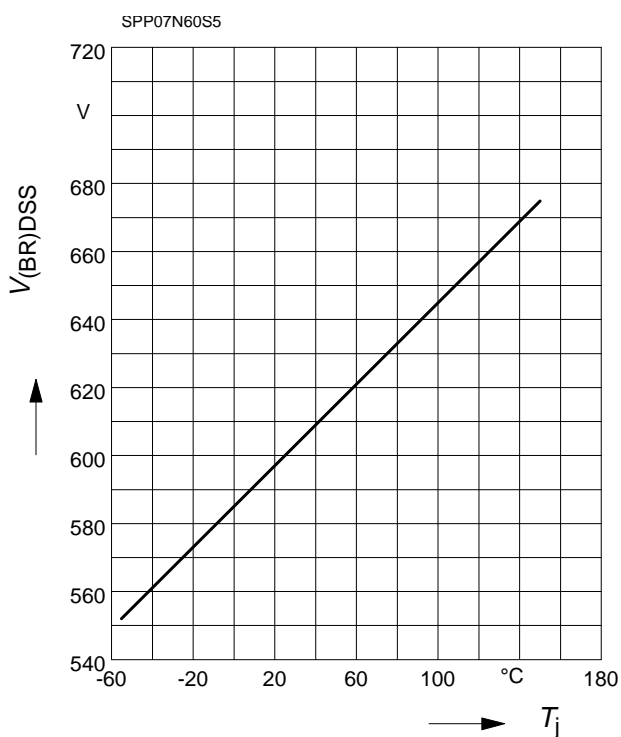
$$I_{AR} = f(t_{AR})$$

par.:  $T_{j(START)} = 25\text{ °C}$ ,  $T_j \leq 150\text{ °C}$



### Drain-source breakdown voltage

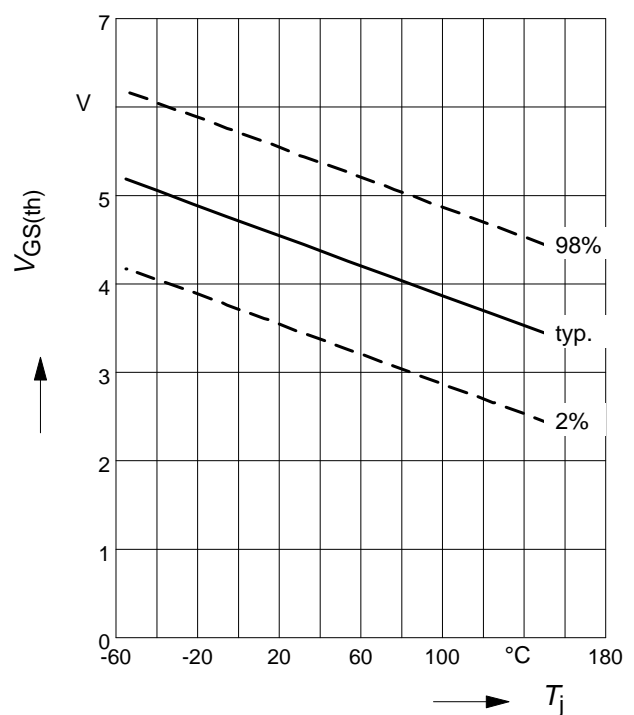
$$V_{(BR)DSS} = f(T_j)$$



### Gate threshold voltage

$$V_{GS(th)} = f(T_j)$$

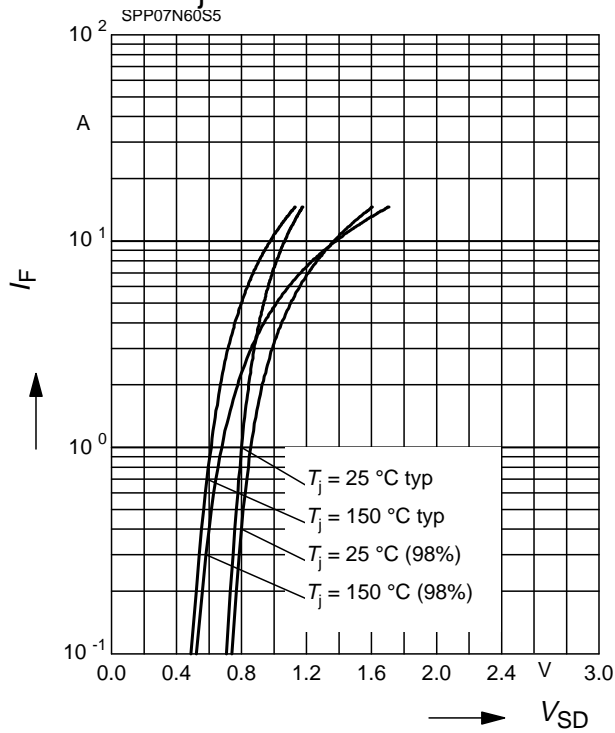
parameter:  $V_{GS} = V_{DS}$ ,  $I_D = 350\text{ μA}$



### Forward characteristics of reverse diode

$$I_F = f(V_{SD})$$

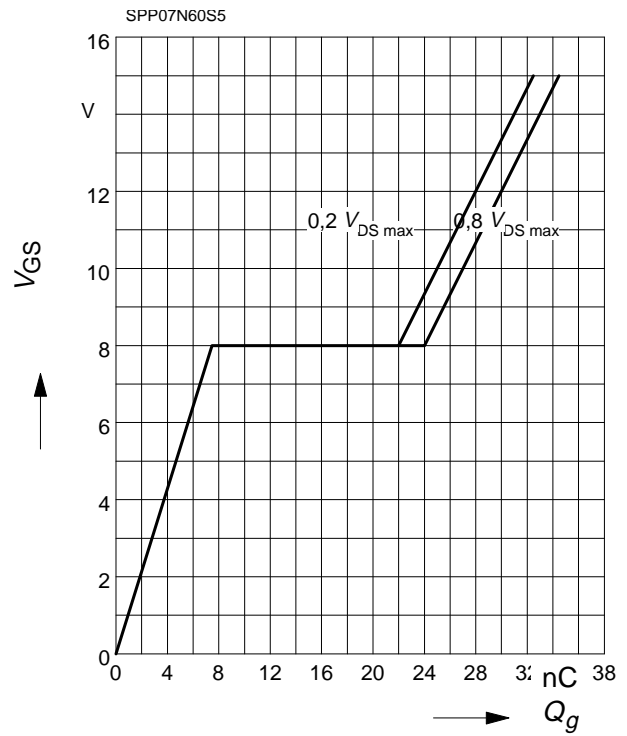
parameter:  $T_j$ ,  $t_p = 80 \mu s$



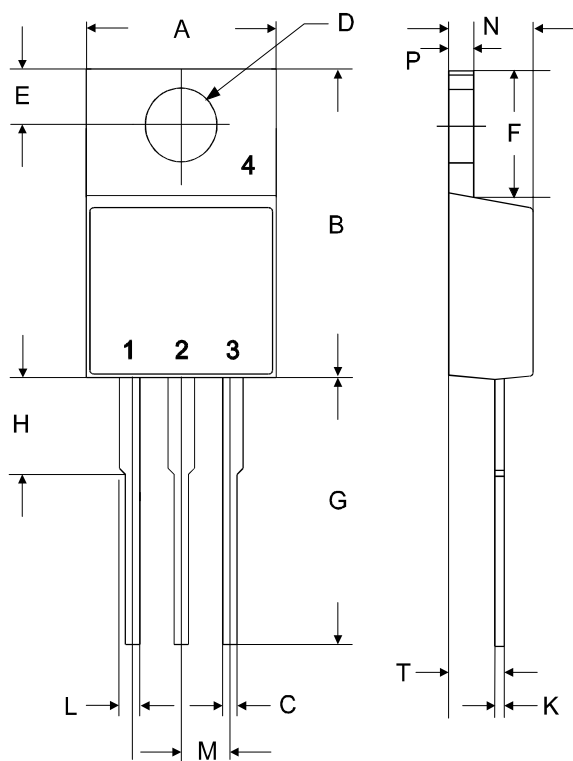
### Typ. gate charge

$$V_{GS} = f(Q_{Gate})$$

parameter:  $I_D = 7.3 \text{ A pulsed}$

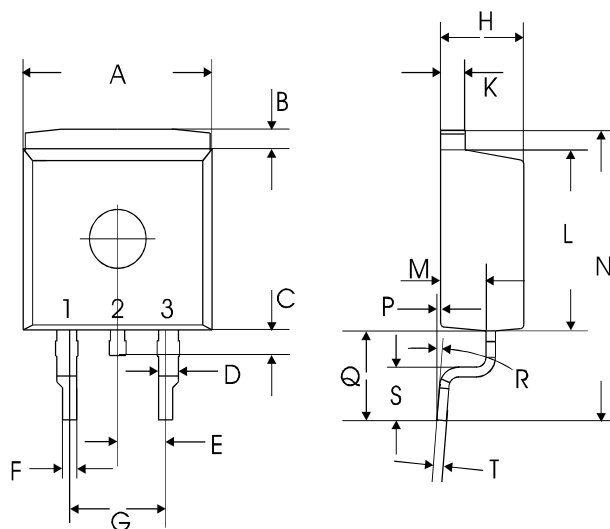


P-TO220-3-1

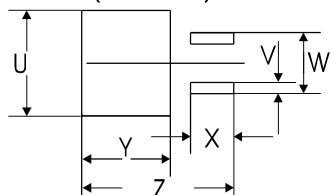


symbol	dimensions			
	[mm]		[inch]	
	min	max	min	max
A	9.70	10.30	0.3819	0.4055
B	14.88	15.95	0.5858	0.6280
C	0.65	0.86	0.0256	0.0339
D	3.55	3.89	0.1398	0.1531
E	2.60	3.00	0.1024	0.1181
F	6.00	6.80	0.2362	0.2677
G	13.00	14.00	0.5118	0.5512
H	4.35	4.75	0.1713	0.1870
K	0.38	0.65	0.0150	0.0256
L	0.95	1.32	0.0374	0.0520
M	2.54 typ.		0.1 typ.	
N	4.30	4.50	0.1693	0.1772
P	1.17	1.40	0.0461	0.0551
T	2.30	2.72	0.0906	0.1071

TO-263 (D<sup>2</sup>Pak/P-TO220SMD)



Footprint  
(dif. scale)



symbol	dimensions			
	[mm]		[inch]	
	min	max	min	max
A	9.80	10.20	0.3858	0.4016
B	0.70	1.30	0.0276	0.0512
C	1.00	1.60	0.0394	0.0630
D	1.03	1.07	0.0406	0.0421
E	2.54 typ.		0.1 typ.	
F	0.65	0.85	0.0256	0.0335
G	5.08 typ.		0.2 typ.	
H	4.30	4.50	0.1693	0.1772
K	1.17	1.37	0.0461	0.0539
L	9.05	9.45	0.3563	0.3720
M	2.30	2.50	0.0906	0.0984
N	15 typ.		0.5906 typ.	
P	0.00	0.20	0.0000	0.0079
Q	4.20	5.20	0.1654	0.2047
R	8° max		8° max	
S	2.40	3.00	0.0945	0.1181
T	0.40	0.60	0.0157	0.0236
U	10.80		0.4252	
V	1.15		0.0453	
W	6.23		0.2453	
X	4.60		0.1811	
Y	9.40		0.3701	
Z	16.15		0.6358	



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